## Two Selectable Inputs, 12 LVPECL Outputs, SiGe Clock Fanout Buffer

## FEATURES

2 selectable differential inputs 4.8 GHz operating frequency 75 fs rms broadband random jitter On-chip input terminations 3.3 V power supply

## APPLICATIONS

## Low jitter clock distribution

Clock and data signal restoration
Level translation
Wireless communications

## Wired communications

Medical and industrial imaging
ATE and high performance instrumentation

## GENERAL DESCRIPTION

The ADCLK954 is an ultrafast clock fanout buffer fabricated on the Analog Devices, Inc., proprietary XFCB3 silicon germanium (SiGe) bipolar process. This device is designed for high speed applications requiring low jitter.

The device has two selectable differential inputs via the IN_SEL control pin. Both inputs are equipped with center tapped, differential, $100 \Omega$ on-chip termination resistors. The inputs accept dc-coupled LVPECL, CML, 3.3 V CMOS (single-ended), and ac-coupled 1.8 V CMOS, LVDS, and LVPECL inputs. A $\mathrm{V}_{\text {Ref }}$ pin is available for biasing ac-coupled inputs.

The ADCLK954 features 12 full-swing emitter coupled logic (ECL) output drivers. For LVPECL (positive ECL) operation, bias $\mathrm{V}_{\mathrm{CC}}$ to the positive supply and $\mathrm{V}_{\mathrm{EE}}$ to ground. For ECL operation, bias $\mathrm{V}_{\mathrm{CC}}$ to ground and $\mathrm{V}_{\mathrm{EE}}$ to the negative supply.
The output stages are designed to directly drive 800 mV each side into $50 \Omega$ terminated to $\mathrm{V}_{\mathrm{CC}}-2 \mathrm{~V}$ for a total differential output swing of 1.6 V .

The ADCLK954 is available in a 40-lead LFCSP and specified for operation over the standard industrial temperature range of $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$.


Figure 1.

Rev. 0

## ADCLK954

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## REVISION HISTORY

3/09—Revision 0: Initial Version

## SPECIFICATIONS

## ELECTRICAL CHARACTERISTICS

Typical (Typ column) values are given for $\mathrm{V}_{\mathrm{CC}}-\mathrm{V}_{\mathrm{EE}}=3.3 \mathrm{~V}$ and $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$, unless otherwise noted. Minimum (Min column) and maximum (Max column) values are given over the full $\mathrm{V}_{\mathrm{CC}}-\mathrm{V}_{\mathrm{EE}}=3.3 \mathrm{~V} \pm 10 \%$ and $\mathrm{T}_{\mathrm{A}}=-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ variation, unless otherwise noted.

Table 1. Clock Inputs and Outputs

| Parameter | Symbol | Min | Typ | Max | Unit | Test Conditions/Comments |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| DC INPUT CHARACTERISTICS <br> Input Voltage High Level <br> Input Voltage Low Level <br> Input Differential Range <br> Input Capacitance <br> Input Resistance <br> Single-Ended Mode <br> Differential Mode <br> Common Mode <br> Input Bias Current <br> Hysteresis | $\begin{aligned} & \mathrm{V}_{\text {H }} \\ & \mathrm{V}_{\text {LID }} \\ & \mathrm{V}_{\text {II }} \end{aligned}$ | $\begin{aligned} & \mathrm{V}_{\mathrm{EE}}+1.6 \\ & \mathrm{~V}_{\mathrm{EE}} \\ & 0.4 \end{aligned}$ | $0.4$ <br> 50 <br> 100 <br> 50 <br> 20 <br> 10 | $V_{c c}$ <br> $V_{\text {cc }}-0.2$ <br> 3.4 | V <br> V <br> V p-p <br> pF <br> $\Omega$ <br> $\Omega$ <br> $\mathrm{k} \Omega$ <br> $\mu \mathrm{A}$ <br> mV | $\pm 1.7 \mathrm{~V}$ between input pins <br> Open $V_{T X}$ |
| DC OUTPUT CHARACTERISTICS <br> Output Voltage High Level <br> Output Voltage Low Level <br> Output Voltage Differential <br> Reference Voltage <br> Output Voltage <br> Output Resistance | $\mathrm{V}_{\mathrm{OH}}$ <br> Vol <br> Vod <br> $V_{\text {REF }}$ | $\begin{aligned} & \mathrm{V}_{\mathrm{Cc}}-1.26 \\ & \mathrm{~V}_{\mathrm{cc}}-1.99 \\ & 610 \end{aligned}$ | $\begin{aligned} & \left(V_{c c}+1\right) / 2 \\ & 235 \end{aligned}$ | $\begin{aligned} & V_{c c}-0.76 \\ & V_{c c}-1.54 \\ & 960 \end{aligned}$ | $\begin{aligned} & \mathrm{V} \\ & \mathrm{~V} \\ & \mathrm{mV} \\ & \mathrm{~V} \\ & \Omega \end{aligned}$ | $\begin{aligned} & 50 \Omega \text { to }\left(\mathrm{V}_{\mathrm{cc}}-2.0 \mathrm{~V}\right) \\ & 50 \Omega \text { to }\left(\mathrm{V}_{\mathrm{cc}}-2.0 \mathrm{~V}\right) \\ & 50 \Omega \text { to }\left(\mathrm{V}_{\mathrm{cc}}-2.0 \mathrm{~V}\right) \\ & -500 \mu \mathrm{~A} \text { to }+500 \mu \mathrm{~A} \end{aligned}$ |

Table 2. Timing Characteristics

| Parameter | Symbol | Min | Typ | Max | Unit | Test Conditions/Comments |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| AC PERFORMANCE <br> Maximum Output Frequency |  | 4.5 | 4.8 |  | GHz | See Figure 4 for differential output voltage vs. frequency, $>0.8 \mathrm{~V}$ differential output swing |
| Output Rise Time | $\mathrm{t}_{\mathrm{R}}$ | 40 | 75 | 90 | ps | 20\% to 80\% measured differentially |
| Output Fall Time | $\mathrm{t}_{\mathrm{F}}$ | 40 | 75 | 90 | ps |  |
| Propagation Delay | $t_{\text {PD }}$ | 175 | 210 | 245 | ps | $\mathrm{V}_{\mathrm{ICM}}=2 \mathrm{~V}, \mathrm{~V}_{\text {ID }}=1.6 \mathrm{~V} \mathrm{p}-\mathrm{p}$ |
| Temperature Coefficient |  |  | 50 |  | fs $/{ }^{\circ} \mathrm{C}$ |  |
| Output-to-Output Skew ${ }^{1}$ |  |  | 9 | 25 | ps |  |
| Part-to-Part Skew |  |  |  | 45 | ps | $\mathrm{V}_{\text {ID }}=1.6 \mathrm{~V} \mathrm{p}-\mathrm{p}$ |
| Additive Time Jitter |  |  |  |  |  |  |
| Integrated Random Jitter |  |  | 28 |  | fs rms | $\mathrm{BW}=12 \mathrm{kHz}-20 \mathrm{MHz}, \mathrm{CLK}=1 \mathrm{GHz}$ |
| Broadband Random Jitter ${ }^{2}$ |  |  | 75 |  | fs rms | $\mathrm{V}_{\mathrm{ID}}=1.6 \mathrm{~V} \mathrm{p}-\mathrm{p}, 8 \mathrm{~V} / \mathrm{ns}, \mathrm{V}_{\mathrm{ICM}}=2 \mathrm{~V}$ |
| Crosstalk-Induced Jitter ${ }^{3}$ |  |  | 90 |  | fs rms |  |
| CLOCK OUTPUT PHASE NOISE <br> Absolute Phase Noise |  |  |  |  |  |  |
|  |  |  |  |  |  | Input slew rate > $1 \mathrm{~V} / \mathrm{ns}$ (see Figure 11, the phase noise plot, for more details) |
| $\mathrm{fiN}_{\mathrm{N}}=1 \mathrm{GHz}$ |  |  | -119 |  | $\mathrm{dBc} / \mathrm{Hz}$ | @100 Hz offset |
|  |  |  | -134 |  | $\mathrm{dBc} / \mathrm{Hz}$ | @1 kHz offset |
|  |  |  | -145 |  | $\mathrm{dBc} / \mathrm{Hz}$ | @10 kHz offset |
|  |  |  | -150 |  | $\mathrm{dBc} / \mathrm{Hz}$ | @100 kHz offset |
|  |  |  | -150 |  | $\mathrm{dBc} / \mathrm{Hz}$ | >1 MHz offset |

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Table 3. Input Select Control Pin

| Parameter | Symbol | Min | Typ | Max | Unit |
| :--- | :--- | :--- | :--- | :--- | :--- |
| Logic 1 Voltage | $\mathrm{V}_{\mathrm{IH}}$ | $\mathrm{V}_{\mathrm{cc}}-0.4$ |  | $\mathrm{~V}_{\mathrm{cc}}$ |  |
| Logic 0 Voltage | $\mathrm{V}_{\mathrm{IL}}$ | $\mathrm{V}_{\mathrm{EE}}$ | V |  |  |
| Logic 1 Current | $\mathrm{I}_{\mathrm{H}}$ |  |  | 1.0 | V |
| Logic 0 Current | $\mathrm{I}_{\mathrm{LL}}$ |  |  | 100 | $\mu \mathrm{~A}$ |
| Capacitance |  |  | 0.6 | mA |  |

Table 4. Power

| Parameter | Symbol | Min | Typ | Max | Unit | Test Conditions/Comments |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| POWER SUPPLY |  |  |  |  |  |  |
| Supply Voltage Requirement | $\mathrm{V}_{\text {CC }}-\mathrm{V}_{\text {EE }}$ | 2.97 |  | 3.63 | V | $3.3 V+10 \%$ |
| Power Supply Current |  |  |  |  |  | Static |
| Negative Supply Current | Ivee |  | 140 | 180 | mA | $V_{\text {CC }}-V_{\text {EE }}=3.3 \mathrm{~V} \pm 10 \%$ |
| Positive Supply Current | Ivce |  | 420 | 470 | mA | $V_{\text {CC }}-V_{\text {EE }}=3.3 \mathrm{~V} \pm 10 \%$ |
| Power Supply Rejection ${ }^{1}$ | PSRucc |  | <3 |  | ps/V | $V_{\text {CC }}-V_{\text {EE }}=3.3 \mathrm{~V} \pm 10 \%$ |
| Output Swing Supply Rejection ${ }^{2}$ | PSRucc |  | 28 |  | dB | $\mathrm{V}_{\text {CC }}-\mathrm{V}_{\text {EE }}=3.3 \mathrm{~V} \pm 10 \%$ |

${ }^{1}$ Change in $t_{\text {PD }}$ per change in $V_{C c}$.
${ }^{2}$ Change in output swing per change in $\mathrm{V}_{\mathrm{cc}}$.

## ABSOLUTE MAXIMUM RATINGS

Table 5.

| Parameter | Rating |
| :---: | :---: |
| Supply Voltage |  |
| $\mathrm{V}_{\text {CC }}-\mathrm{V}_{\text {EE }}$ | 6.0 V |
| Input Voltage |  |
| CLK0, CLK1, $\overline{\mathrm{CLKO}}, \overline{\mathrm{CLK1}}, \mathrm{IN}$ _SEL | $\begin{aligned} & \mathrm{V}_{\mathrm{EE}}-0.5 \mathrm{~V} \text { to } \\ & \mathrm{V}_{\mathrm{CC}}+0.5 \mathrm{~V} \end{aligned}$ |
| CLK0, CLK1, $\overline{\mathrm{CLKO}}, \overline{\mathrm{CLK} 1}$ to $\mathrm{V}_{\mathrm{T} X}$ Pin (CML, LVPECL Termination) | $\pm 40 \mathrm{~mA}$ |
| CLK0, CLK1 to $\overline{\text { CLKO }}$, $\overline{\text { CLK1 }}$ | $\pm 1.8 \mathrm{~V}$ |
| ```Input Termination, \(\mathrm{V}_{T} \times\) to CLKO, CLK1, \(\overline{\mathrm{CLKO}}\), and CLK1``` | $\pm 2 \mathrm{~V}$ |
| Maximum Voltage on Output Pins | $\mathrm{V}_{\text {cc }}+0.5 \mathrm{~V}$ |
| Maximum Output Current | 35 mA |
| Voltage Reference ( $\mathrm{V}_{\text {gEF }}$ ) | $\mathrm{V}_{\text {CC }}$ to $\mathrm{V}_{\mathrm{EE}}$ |
| Operating Temperature Range |  |
| Ambient | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ |
| Junction | $150^{\circ} \mathrm{C}$ |
| Storage Temperature Range | $-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$ |

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## DETERMINING JUNCTION TEMPERATURE

To determine the junction temperature on the application printed circuit board (PCB), use the following equation:

$$
T_{J}=T_{C A S E}+\left(\Psi_{J T} \times P_{D}\right)
$$

where:
$T_{J}$ is the junction temperature ( ${ }^{\circ} \mathrm{C}$ ).
$T_{\text {CASE }}$ is the case temperature $\left({ }^{\circ} \mathrm{C}\right)$ measured by the customer at the top center of the package.
$\Psi_{J T}$ is from Table 6.
$P_{D}$ is the power dissipation.
Values of $\theta_{\text {JA }}$ are provided for package comparison and PCB design considerations. $\theta_{\mathrm{JA}}$ can be used for a first-order approximation of $\mathrm{T}_{\mathrm{J}}$ by the equation

$$
T_{J}=T_{A}+\left(\theta_{I A} \times P_{D}\right)
$$

where $T_{A}$ is the ambient temperature $\left({ }^{\circ} \mathrm{C}\right)$.
Values of $\theta_{\text {Jв }}$ are provided in Table 6 for package comparison and PCB design considerations.

## ESD CAUTION

|  | ESD (electrostatic discharge) sensitive device. <br> Charged devices and circuit boards can discharge <br> without detection. Although this product features <br> patented or proprietary protection circuitry, damage |
| :--- | :--- |
| may occur on devices subjected to high energy ESD. |  |
| Therefore, proper ESD precautions should be taken to |  |
| avoid performance degradation or loss of functionality. |  |

## THERMAL PERFORMANCE

Table 6.

| Parameter | Symbol | Description | Value ${ }^{1}$ | Unit |
| :---: | :---: | :---: | :---: | :---: |
| Junction-to-Ambient Thermal Resistance | $\theta_{\text {JA }}$ |  |  |  |
| Still Air $0.0 \mathrm{~m} / \mathrm{sec}$ Air Flow |  | Per JEDEC JESD51-2 | 46.1 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Moving Air | $\theta$ נма | Per JEDEC JESD51-6 |  |  |
| $1.0 \mathrm{~m} / \mathrm{sec}$ Air Flow |  |  | 40.3 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| $2.5 \mathrm{~m} / \mathrm{sec}$ Air Flow |  |  | 36.2 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Junction-to-Board Thermal Resistance | $\theta_{\text {лв }}$ |  |  |  |
| Moving Air $1.0 \mathrm{~m} / \mathrm{sec}$ Air Flow |  | Per JEDEC JESD51-8 | 28.7 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Junction-to-Case Thermal Resistance | $\theta_{\mathrm{jc}}$ |  |  |  |
| Moving Air Die-to-Heatsink |  | Per MIL-STD 883, Method 1012.1 | 8.3 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Junction-to-Top-of-Package Characterization Parameter | $\Psi_{\text {JT }}$ |  |  |  |
| Still Air <br> $0 \mathrm{~m} / \mathrm{sec}$ Air Flow |  | Per JEDEC JESD51-2 | 0.6 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |

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## PIN CONFIGURATION AND FUNCTION DESCRIPTIONS



Figure 2. Pin Configuration
Table 7. Pin Function Descriptions

| Pin No. | Mnemonic | Description |
| :---: | :---: | :---: |
| 1 | IN_SEL | Input Select. Logic 0 selects CLK0 and $\overline{\text { CLK0 }}$ inputs. Logic 1 selects CLK1 and $\overline{\text { CLK1 }}$ inputs. |
| 2 | CLK0 | Differential Input (Positive) 0. |
| 3 | $\overline{\text { CLKO }}$ | Differential Input (Negative) 0. |
| 4 | $\mathrm{V}_{\text {ReF }} \mathrm{O}$ | Reference Voltage. Reference voltage for biasing ac-coupled CLKO and $\overline{\text { CLKO }}$ inputs. |
| 5 | VT0 | Center Tap. Center tap of a $100 \Omega$ input resistor for CLK0 and $\overline{\text { CLKO }}$ inputs. |
| 6 | CLK1 | Differential Input (Positive) 1. |
| 7 | $\overline{\text { CLK1 }}$ | Differential Input (Negative) 1. |
| 8 | $\mathrm{V}_{\mathrm{T}} 1$ | Center Tap. Center tap of a $100 \Omega$ input resistor for CLK1 and $\overline{\text { CLK1 }}$ inputs. |
| 9 | $V_{\text {REF }} 1$ | Reference Voltage. Reference voltage for biasing ac-coupled CLK1 and CLK1 inputs. |
| 10 | $V_{\text {EE }}$ | Negative Supply Pin. |
| $\begin{aligned} & 11,20,21, \\ & 30,31,40 \end{aligned}$ | Vcc | Positive Supply Pin. |
| 12,13 | $\overline{\text { Q11, Q11 }}$ | Differential LVPECL Outputs. |
| 14,15 | Q10, Q10 | Differential LVPECL Outputs. |
| 16,17 | $\overline{\mathrm{Q}}$, Q9 | Differential LVPECL Outputs. |
| 18, 19 | Q8, Q8 | Differential LVPECL Outputs. |
| 22, 23 | Q7, Q7 | Differential LVPECL Outputs. |
| 24,25 | Q6, Q6 | Differential LVPECL Outputs. |
| 26,27 | $\overline{\mathrm{Q}}, \mathrm{Q} 5$ | Differential LVPECL Outputs. |
| 28,29 | $\overline{\mathrm{Q} 4}$, Q4 | Differential LVPECL Outputs. |
| 32,33 | Q3, Q3 | Differential LVPECL Outputs. |
| 34,35 | $\overline{\mathrm{Q} 2}$, Q2 | Differential LVPECL Outputs. |
| 36,37 | $\overline{\mathrm{Q} 1}, \mathrm{Q} 1$ | Differential LVPECL Outputs. |
| 38,39 | Q0, Q0 | Differential LVPECL Outputs. |
| (41) | EPAD | EPAD must be connected to $\mathrm{V}_{\text {EE }}$. |

## TYPICAL PERFORMANCE CHARACTERISTICS

$\mathrm{V}_{\mathrm{CC}}=3.3 \mathrm{~V}, \mathrm{~V}_{\mathrm{EE}}=0.0 \mathrm{~V}, \mathrm{~V}_{\mathrm{ICM}}=\mathrm{V}_{\mathrm{REF}}, \mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$, clock outputs terminated at $50 \Omega$ to $\mathrm{V}_{\mathrm{CC}}-2 \mathrm{~V}$, unless otherwise noted.


Figure 3. LVPECL Output Waveform @ 200 MHz


Figure 4. Differential Output Voltage vs. Frequency,
$V_{I D}>1.1 \mathrm{Vp}-p$


Figure 5. Propagation Delay vs. Differential Input Voltage


Figure 6. LVPECL Output Waveform @ 1000 MHz


Figure 7. Propagation Delay vs. Temperature, $V_{I D}=1.6 \mathrm{Vp}-\mathrm{p}$


Figure 8. Propagation Delay vs. DC Common-Mode Voltage vs. Temperature, Input Slew Rate > 25 V/ns

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Figure 9. Differential Output Voltage Swing vs. Power Supply Voltage vs. Temperature, $V_{I D}=1.6 \mathrm{~V} p-p$


Figure 10. Power Supply Current vs. Power Supply Voltage vs. Temperature, All Outputs Loaded ( $50 \Omega$ to $V_{c c}-2$ V)


Figure 11. Absolute Phase Noise Measured @1 GHz


Figure 12. RMS Random Jitter vs. Input Slew Rate, VID Method

## FUNCTIONAL DESCRIPTION

## clock INPUTS

The ADCLK954 accepts a differential clock input from one of two inputs and distributes the selected clock to all 12 LVPECL outputs. The maximum specified frequency is the point at which the output voltage swing is $50 \%$ of the standard LVPECL swing (see Figure 4). See the functional block diagram (Figure 1) and the General Description section for more clock input details. See Figure 19 through Figure 22 for various clock input termination schemes.

Output jitter performance is degraded by an input slew rate below $4 \mathrm{~V} / \mathrm{ns}$, as shown in Figure 12. The ADCLK954 is specifically designed to minimize added random jitter over a wide input slew rate range. Whenever possible, clamp excessively large input signals with fast Schottky diodes because attenuators reduce the slew rate. Input signal runs of more than a few centimeters should be over low loss dielectrics or cables with good high frequency characteristics.

## CLOCK OUTPUTS

The specified performance necessitates using proper transmission line terminations. The LVPECL outputs of the ADCLK954 are designed to directly drive 800 mV into a $50 \Omega$ cable or into microstrip/stripline transmission lines terminated with $50 \Omega$ referenced to $\mathrm{V}_{\mathrm{CC}}-2 \mathrm{~V}$, as shown in Figure 14. The LVPECL output stage is shown in Figure 13. The outputs are designed for best transmission line matching. If high speed signals must be routed more than a centimeter, either the microstrip or the stripline technique is required to ensure proper transition times and to prevent excessive output ringing and pulse width dependent propagation delay dispersion.


Figure 13. Simplified Schematic Diagram of the LVPECL Output Stage
Figure 14 through Figure 17 depict various LVPECL output termination schemes. When dc-coupled, $\mathrm{V}_{\mathrm{s}}$ of the receiving buffer should match the VS_DRV.

Thevenin-equivalent termination uses a resistor network to provide $50 \Omega$ termination to a dc voltage that is below Vol of the LVPECL driver. In this case, VS_DRV on the ADCLK954 should equal $\mathrm{V}_{\mathrm{S}}$ of the receiving buffer. Although the resistor combination shown (in Figure 15) results in a dc bias point of VS_DRV - 2 V , the actual common-mode voltage is VS_DRV 1.3 V because there is additional current flowing from the ADCLK954 LVPECL driver through the pull-down resistor.
LVPECL Y-termination is an elegant termination scheme that uses the fewest components and offers both odd- and even-mode impedance matching. Even-mode impedance matching is an important consideration for closely coupled transmission lines at high frequencies. Its main drawback is that it offers limited flexibility for varying the drive strength of the emitter follower LVPECL driver. This can be an important consideration when driving long trace lengths, but is usually not an issue.


Figure 14. DC-Coupled, 3.3 VLVPECL


Figure 15. DC-Coupled, 3.3 V LVPECL Far-End Thevenin Termination


Figure 16. DC-Coupled, 3.3 VLVPECL Y-Termination


Figure 17. AC-Coupled, LVPECL with Parallel Transmission Line

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## CLOCK INPUT SELECT (IN_SEL) SETTINGS

A Logic 0 on the IN_SEL pin selects the Input CLK0 and Input $\overline{\mathrm{CLK0}}$. A Logic 1 on the IN_SEL pin selects Input CLK1 and Input $\overline{\text { CLK1 }}$.

## PCB LAYOUT CONSIDERATIONS

The ADCLK954 buffer is designed for very high speed applications. Consequently, high speed design techniques must be used to achieve the specified performance. It is critically important to use low impedance supply planes for both the negative supply $\left(\mathrm{V}_{\mathrm{EE}}\right)$ and the positive supply ( $\mathrm{V}_{\mathrm{CC}}$ ) planes as part of a multilayer board. Providing the lowest inductance return path for switching currents ensures the best possible performance in the target application.
The following references to GND plane assume that the $\mathrm{V}_{\mathrm{EE}}$ power plane is grounded for LVPECL operation. Note that for ECL operation, the $\mathrm{V}_{\mathrm{CC}}$ power plane becomes the ground plane.

It is also important to adequately bypass the input and output supplies. Place a $1 \mu \mathrm{~F}$ electrolytic bypass capacitor within several inches of each $V_{C C}$ power supply pin to the GND plane. In addition, place multiple high quality $0.001 \mu \mathrm{~F}$ bypass capacitors as close as possible to each of the $\mathrm{V}_{\mathrm{CC}}$ supply pins and connect the capacitors to the GND plane with redundant vias. Carefully select high frequency bypass capacitors for minimum inductance and ESR. To improve the effectiveness of the bypass at high frequencies, minimize parasitic layout inductance. Also, avoid discontinuities along input and output transmission lines that can affect jitter performance.

In a $50 \Omega$ environment, input and output matching have a significant impact on performance. The buffer provides internal $50 \Omega$ termination resistors for both CLKx and CLKx inputs. Normally, the return side is connected to the reference pin that is provided. Carefully bypass the termination potential using ceramic capacitors to prevent undesired aberrations on the input signal due to parasitic inductance in the termination
return path. If the inputs are dc-coupled to a source, take care to ensure that the pins are within the rated input differential and common-mode ranges.

If the return is floated, the device exhibits a $100 \Omega$ cross termination, but the source must then control the common-mode voltage and supply the input bias currents.

There are ESD/clamp diodes between the input pins to prevent the application from developing excessive offsets to the input transistors. ESD diodes are not optimized for best ac performance. When a clamp is required, it is recommended that appropriate external diodes be used.

## Exposed Metal Paddle

The exposed metal paddle on the ADCLK954 package is both an electrical connection and a thermal enhancement. For the device to function properly, the paddle must be properly attached to the $V_{\text {EE }}$ power plane.

When properly mounted, the ADCLK954 also dissipates heat through its exposed paddle. The PCB acts as a heat sink for the ADCLK954. The PCB attachment must provide a good thermal path to a larger heat dissipation area. This requires a grid of vias from the top layer down to the $\mathrm{V}_{\text {EE }}$ power plane (see Figure 18). The ADCLK954 evaluation board (ADCLK954/PCBZ) provides an example of how to attach the part to the PCB.


## INPUT TERMINATION OPTIONS



Figure 19. Interfacing to CML Inputs


Figure 20. Interfacing to PECL Inputs


Figure 21. AC Coupling Differential Signals Inputs, Such As LVDS


CONNECT $V_{T}, V_{\text {REF }}$, AND $\overline{\text { CLK. }}$. PLACE A BYPASS CAPACITOR FROM $V_{T}$ TO GROUND.
ALTERNATIVELY, $V_{T}$, $V_{\text {REF }}$, AND CLK CAN BE ALTERNATIVELY, $V_{T}, V_{\text {REF }}$, AND CLK CAN BE CONNECTED, GIVING
A $180^{\circ}$ PHASE SHIFT.
Figure 22. Interfacing to AC-Coupled Single-Ended Inputs

## ADCLK954

## OUTLINE DIMENSIONS



COMPLIANT TO JEDEC STANDARDS MO-220-VJJD-2
Figure 23. 40-Lead Lead Frame Chip Scale Package [LFCSP_VQ]
$6 \mathrm{~mm} \times 6 \mathrm{~mm}$ Body, Very Thin Quad (CP-40-8)
Dimensions shown in millimeters

## ORDERING GUIDE

| Model | Temperature Range | Package Description | Package Option |
| :--- | :--- | :--- | :--- |
| ADCLK954BCPZ $^{1}$ | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | $40-$ Lead LFCSP_VQ | CP-40-8 |
| ADCLK954BCPZ-REEL7 1 | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | $40-$ Lead LFCSP_VQ | CP-40-8 |
| ADCLK954/PCBZ $^{1}$ |  | Evaluation Board |  |

${ }^{1} Z=$ RoHS Compliant Part.


[^0]:    ${ }^{1}$ The output skew is the difference between any two similar delay paths while operating at the same voltage and temperature.
    ${ }^{2}$ Measured at the rising edge of the clock signal; calculated using the SNR of the ADC method.
    ${ }^{3}$ This is the amount of added jitter measured at the output while two related, asynchronous, differential frequencies are applied to the inputs.

[^1]:    ${ }^{1}$ Results are from simulations. The PCB is a JEDEC multilayer type. Thermal performance for actual applications requires careful inspection of the conditions in the application to determine if they are similar to those assumed in these calculations.

